

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/744,003	<b>Applicant(s)/Patent under Reexamination</b> KOMATSU ET AL.
<b>Examiner</b> Leith A. Al-Nazer	<b>Art Unit</b> 2821	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
343	711, 712	3/16/2005	LA
343	713	3/16/2005	LA
343	767, 769	3/16/2005	LA
343/789, 700MS		3/16/2005	LA